

<b>Search Notes</b>				Application/Control No.	Applicant(s)/Patent under Reexamination	
				10/656,055	YAVER ET AL.	
				Examiner	Art Unit	
				Ja-Na Hines	1645	

<b>SEARCHED</b>			
Class	Subclass	Date	Examiner
424	9.2, 94.1, 116, 278.1	2/6/2006	JAH
435	4, 7.2		
	7.31,		
	7.32, 7.4		
	7.95, 32		
	71.3, 243		
	244,		
	252.1		
	254.1		
	255.1		
436	2		
<i>Updated previous searches</i>			

<b>SEARCH NOTES (INCLUDING SEARCH STRATEGY)</b>		
	DATE	EXMR
STIC, west, deerwent, biosis, argicola, caplus, japiom eplus, scisearch, medline, biotechno, commerical databases, inventor	2/6/2006	JAH
<i>Updated previous searches</i>	9/07	<i>JK</i>

<b>INTERFERENCE SEARCHED</b>			
Class	Subclass	Date	Examiner